Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/700,249	MATSUI ET AL.
Examiner	Art Unit
Jacob Cheu	1641

SEARCHED							
Class	Subclass	Date	Examiner				
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
FAST STN Searl Zurenta	3/2/66	X		
Consided with Pand Sannder with tem "fragment" in Claim 14.	3/5/06	Ĵ∪		
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